Special Issue

Remote Sensing Image Processing and Application

Message from the Guest Editors

Today, it is easy to obtain remote sensing images from different types of sensors, such as hyperspectral, multispectral, LiDAR, etc. Remote sensing images are one of the fastest-growing research areas because of their wide range of applications. As remote sensing technologies and methods continue to improve in recent decades, scientists have made great strides in the field of remote sensing image processing. Satellite, airborne, UAV, and terrestrial imaging techniques are constantly evolving in terms of data volume, quality, and variety. Remarkable efforts have been made to improve interpretation accuracy, subpixel-level classification, and many other aspects. This Special Issue will be a collection of articles focusing on new insights, new developments, current challenges, and future prospects in the field of remote sensing image processing. It aims to present the latest advances in innovative image analysis and processing techniques and their contribution to a wide range of application areas, in an effort to predict where they will take the discipline and practice in the coming years.

Guest Editors

Prof. Dr. Weitao Chen

Dr. Ailong Ma

Prof. Dr. Guohua Wu

Deadline for manuscript submissions

closed (31 December 2023)

About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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